

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10772805	KEENAN, MICHAEL R.
	<b>Examiner</b>	<b>Art Unit</b>
	Abdelnour, Farris	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	232-253	4/23/2008	ms
356	300-305	4/23/2008	ms
375	240,240.01-240.24	4/23/2008	ms

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
keenan-michael\$.in.	6/14/2007	FA
(concentration ADJ3 matrix) AND (spectral ADJ3 shape) AND wavelet	6/18/2007	FA
(principal ADJ3 component\$) AND wavelet\$ AND concentration AND image	6/18/2007	FA
(scor\$ ADJ3 matrix) AND (loading ADJ3 matrix) AND wavelet	6/18/2007	FA
((principal\$ ADJ3 component\$) OR SVD) AND matrix AND image AND wavelet	6/18/2007	FA
(data ADJ3 factor) AND (concentration ADJ3 matrix) AND (spectral ADJ3 shape) AND wavelet	6/19/2007	FA
Updated search, US-PGPUB, USPAT, EPO, JPO	11/26/2007	FA
East Search Updated	4/23/2008	ms
Inventor Search	4/23/2008	ms
STIC Plus Search	4/23/2008	ms
Interference Search	4/23/2008	ms
IEEE Search	4/23/2008	ms

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	PGPUB Text Search - see attached search notes	4/23/2008	ms